

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	semiconductor and drain and source and gate and (dummy) and (sidewall near5 (insulating or dielectric)) and (linear adj contact)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:06
L2	460	semiconductor and drain and source and gate and (dummy) and (sidewall near5 (insulating or dielectric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:06
L3	32	semiconductor and drain and source and gate and (dummy adj electrode) and (sidewall near5 (insulating or dielectric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:06
L4	32	semiconductor and drain and source and gate and (dummy adj electrode) and (sidewall near5 (insulating or dielectric)) and (gate adj electrode)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:06
L5	10	semiconductor and drain and source and gate and (dummy adj electrode) and (sidewall near5 (insulating or dielectric)) and (gate adj electrode) and ((gate adj electrode) with (dummy electrode) with (sidewall adj (insulating or dielectric)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:09

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L8	20	I7 and (gate with dummy with sidewall with (insulating or dielectric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:10
L9	12	I7 and (gate with dummy with sidewall with (insulating or dielectric)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:11
L10	12	I7 and (gate with dummy with sidewall with (insulating or dielectric) with electrode).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:11
L11	1	I7 and (gate with dummy with sidewall with (insulating or dielectric) with electrode with contact).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:11
L12	12	I7 and (gate with dummy with sidewall with (insulating or dielectric) with electrode).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:11
L13	5	(gate with dummy with sidewall with (insulating or dielectric) with electrode with (view or viewing or viewed))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:12
L14	5	(gate with dummy with (sidewall near5 (insulating or dielectric)) with electrode with (view or viewing or viewed))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:12
L15	70	(gate with dummy with (sidewall near5 (insulating or dielectric)) with electrode)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:12
L16	21	(gate with dummy with (sidewall near5 (insulating or dielectric)) with electrode with contact)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:13

L17	2	(gate with dummy with (sidewall near5 (insulating or dielectric)) with electrode with (linear adj contact))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:13
L18	340	(linear adj contact) and electrode	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:13
L19	29	(linear adj contact) and electrode and gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:13
L20	2	(linear adj contact) and electrode and gate and dummy	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:14
L21	29	(linear adj contact) and electrode and gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:15
L22	550	((view of viewing or viewed) near3 above) and dummy and electrode and gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:16
L23	108	((view of viewing or viewed) near3 above) and dummy and electrode and gate and sidewall	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:16
L24	5	((view of viewing or viewed) near3 above) with dummy and electrode and gate and sidewall	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:16
L25	2	((view of viewing or viewed) near3 above) with dummy with electrode and gate and sidewall	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:16
L26	1	(((view of viewing or viewed) near3 above) and dummy and electrode and gate and sidewall). clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:16

L27	2	((view of viewing or viewed) near3 above) and dummy and electrode and gate and sidewall). ti,ab,clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L28	2	((view of viewing or viewed) near3 (top or above)) and dummy and electrode and gate and sidewall).ti,ab,clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L29	314	((view of viewing or viewed) near3 (top or above)) and dummy and electrode and gate and sidewall)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L30	63	((view of viewing or viewed) near3 (top or above)) and dummy. clm. and electrode and gate and sidewall)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L31	27	((view of viewing or viewed) near3 (top or above)) and dummy. clm. and electrode and gate and sidewall.clm.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L32	21	((view of viewing or viewed) near3 (top or above)) and dummy. clm. and electrode.clm. and gate and sidewall.clm.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17
L33	21	((view of viewing or viewed) near3 (top or above)) and dummy. clm. and electrode.clm. and gate. clm. and sidewall.clm.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/06 17:17